Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/830,049	OHNISHI ET AL.
Examiner	Art Unit
Linh V. Nguyen	2819

SEARCHED					
Class	Subclass	Date	Examiner		
330	286,295 277	4/5/2006	LN		
			=		
		-			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u></u>				

SEARCH N (INCLUDING SEAR	NOTES CH STRATEGY	')
	DATE	EXMR
See East searched printout	4/5/2006	LN